APPLIED SCIENCE DEPARTMENT

Sample Analysis using AFM & PLS

Following equipments of Nanotechnology laboratory are available for Sample Characterization and Analysis at approved charges:

1. **Atomic Force Microscope (AFM):** Atomic Size/ Topographic Measurements
   Instrument: Advance-Tech (USA)_ AFM Workshop (TT)
   Modes: Vibrating, Non-vibrating
   Scanner: 50 Micron XYZ scanner;
   XY Resolution: <3nm closed loop, <0.3nm open loop
   Z sensor noise: <5nm
   Probes: Industry standard (Si - Cantilever)
   Sensor: Light lever AFM force sensor
   Sample: Solid, Pellet or thin film on substrate (1×1 inch) in size
   Software: AFM image recording; Gwyddion for Image Analysis

   Charges: Academic Institutes: Rs. 1200/- per sample
   Industry/Others: Rs. 2500/- per sample

2. **Photo Luminescence Spectrometer (PLS):** Optical Properties of Materials
   Instrument: Shimadzu _ Spectrofluorophotometer (RF 5301PC)
   Light Source: Xenon lamp, Monochromator
   Wavelength Scan range: 200-900 nm
   Wavelength Measurement range: 220-750 nm
   Detector: PMT,
   S/N ratio: 150 or more at Raman peak of distilled water
   Temperature Range: 5°C to 80°C
   Sample: Liquid, Powder, Solid: Pellet or Thin film (1×1 inch)
   Software: Data acquisition, File operation, Data manipulation

   Charges: Academic Institutes: Rs. 150/- per sample
   Industry/Others: Rs. 300/- per sample

- Researchers/User has to come personally with prior appointment for sample analysis. GST @ 18% will be charged extra. Charges may be paid in cash or DD in favor of Director, NITTTR Chandigarh.

For appointment: Contact **Professor (Dr.) BC Choudhary**,
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Note: Please bring CDROM for soft copy of data, Images and Spectrums.